

Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Atty Docket No.	BRIDP004
	Application No.:	09/724,585
	Applicant	Beardslee et al.
	Filing Date	November 28, 2000
	Group	Unknown
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Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
<i>K/N</i>	A.	4,306,286	12/1981	Cocke et al.	703	15	
<i>K/N</i>	B.	4,590,581	05/1986	Widdoes, Jr.	703	2	
<i>K/N</i>	C.	4,635,218	01/1987	Widdoes, Jr.	703	14	
<i>K/N</i>	D.	4,675,646	06/1987	Lauer	340	146.2	
<i>K/N</i>	E.	4,845,712	07/1989	Sanner et al.	714	736	
<i>K/N</i>	F.	4,901,259	02/1990	Watkins	703	2	
<i>K/N</i>	G.	4,937,770	06/1990	Samuels et al.	703	16	
<i>K/N</i>	H.	4,937,827	06/1990	Beck et al.	714	33	
<i>K/N</i>	I.	5,036,473	07/1991	Butts et al.	703	23	
<i>K/N</i>	J.	5,146,460	09/1992	Ackerman et al.	714	33	
<i>K/N</i>	K.	5,281,864	01/1994	Hahn et al.	—	—	
<i>K/N</i>	L.	5,321,828	06/1994	Phillips et al.	—	—	
<i>K/N</i>	M.	5,329,470	07/1994	Sample et al.	—	—	
<i>K/N</i>	N.	5,329,471	07/1994	Swoboda et al.	—	—	
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<i>K/N</i>	P.	5,425,036	06/1995	Liu et al.	—	—	
<i>K/N</i>	Q.	5,537,580	07/1996	Giomi et al.	—	—	
<i>K/N</i>	R.	5,546,562	08/1996	Patel	—	—	
<i>K/N</i>	S.	5,560,009	09/1996	Lenkov et al.	—	—	
<i>K/N</i>	T.	5,574,388	11/1996	Barbier et al.	—	—	
<i>K/N</i>	U.	5,581,742	12/1996	Lin et al.	—	—	
<i>K/N</i>	V.	5,596,587	01/1997	Douglas et al.	—	—	
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<i>K/N</i>	X.	5,644,515	07/1997	Sample et al.	—	—	
<i>K/N</i>	Y.	5,663,900	09/1997	Bhandari et al.	—	—	
<i>K/N</i>	Z.	5,748,875	05/1998	Tzori	—	—	
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<i>K/N</i>	FF.	5,805,859	09/1998	Giramma et al.	—	—	
<i>K/N</i>	GG.	5,812,414	09/1998	Butts et al.	—	—	
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KJN	KK.	5,907,697	05/1999	Barbier et al.	—	—	
KJN	LL.	5,937,190	08/1999	Gregory et al.	—	—	
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KJN	UU.	6,057,706	05/2000	Barbier et al.	—	—	
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KJW	C.	5,661,662	08/1997	Butts et al.	716	16	
KJW	D.	6,014,334	01/2000	Patel et al.	365	139.08	
KJW	E.	6,182,247	01/2001	Herrmann et al.	714	39	

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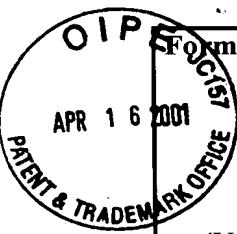
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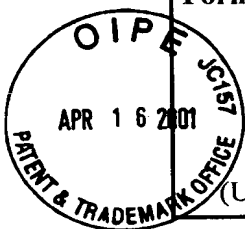
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KJN	O.	Synopsys, Inc., "BSD Compiler" datasheet, www.synopsys.com/products/test/bsd_ds.html .
KJN	P.	Synopsys, Inc., "DFT Compiler" Next Generation 1-Pass Test Synthesis Technology Backgrounder, April 2000.
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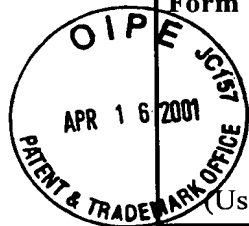


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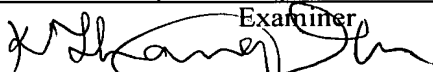
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	Applicant: BEARDSLEE et al.	Group 2819
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Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
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K/M	2	5,831,868	11/03/98	Beausang et al.	364	489	12/09/97
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K/M	5	PCT International Search Report, re PCT/US 00/32543, 28.06.01
K/M	6	U.S. Patent Application No. 09/724,840, filed 11/28/00
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